

COMPLIANCE ASSESMENT WITH DIRECTIVE 2014/30/EU

Equipment name: Part number:

Test report no: CEM Release:0

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1 Purpose

The following test report presents all the results obtained at assessment test on .

2 List of standards and tests performed

Based on product standards :

EN 61000-6-1:2007,

EN 61000-6-3:2007+A1:2011+AC:2012

Applied test standards:

EN 61000-4-2: 2009,

EN 61000-4-3: 2006 / A1 : 2008 / A2 : 2010,

EN 61000-4-4: 2012,

EN 61000-4-5: 2014 / A1: 2017,

EN 61000-4-6: 2014,

EN 61000-4-11: 2004 / A1: 2017,

EN 55022:2010 EN 61000-3-2: 2014 EN 61000-3-3: 2013

Tests	Procedure	Severity of levels			
	Immunity to	ests			
1. Repetitive electrical fast transients	EN 61000-4-4	2 kV on main; 1 kV on other circuits	A		
2. Surge immunity test	EN 61000-4-5	2kV on main; 1kV on other circuits	A		
3. Electrostatic discharge	EN 61000-4-2	8kV on the air; 6kV contact	A		
4. Radiated electromagnetic field	EN 61000-4-3	3V/m; 10V/m	A		
5. Conducted disturbances	EN 61000-4-6	3V/m; 10V/m	A		
6. Voltage dips and variations	EN 61000-4-11	60%, 200ms; 100%, 100ms	A		
E	mission measur	rements			
7. Radiated emissions	EN 55022	Within the limits	A		
8. Conducted disturbances	EN 55022	Within the limits	A		
Other emission measurements					
9. Harmonic current emissions	EN 61000-3-2	Within the limits	N/A		
10. Voltage fluctuations and flicker	EN 61000-3-3	Within the limits	N/A		

A: test case apply to the test object

N/A: test case does not apply to the test object

N/R: No performed

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3 Description and features of the equipment under test Voltage supply: Consumption: Electronic card release: 4 Wiring diagram

Montage.jpg

- 5 Test setup
- 6 Operating mode

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7 Abbrevations used in this report

FC : Normal behavor FI : Abnormal behavor

P: Pass F : Fail

Behavor criteria:

- 1. normal behavor;
- 2. Temporary deterioration or self-recovering loss of function when the disturbance is removed;
- 3. Temporary deterioration or loss of function requiring a reset of the system or the intervention of an operator;
- 4. Temporary deterioration or loss of non-recoverable function due to damage.

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8 Rapid transient immunity tests in bursts on supply circuits

Standard: EN 61000-4-4

Test equipment: Haefely PEFT Junior

8.1 Test conditions

See wiring diagram.

tm:5nstd:50ns

Burts duration: 15ms

Period: 300ms

Test duration: 60s minimum

8.2 Test results

8.2.1 On power ports

Level	Voltage	Remark	Result	Verdict
1	+/- 0.5 kV	FC	1	С
2	+/- 1 kV	FC	1	С
3	+/- 2 kV	FC	1	С
X	+/- 3-4 kV	FC	1	C

8.2.2 On I/O signal, data and control ports

Level	Volatge	Remark	Result	Verdict
1	+/- 0.5 kV	FC	1	С
2	+/- 1 kV	FC	1	С
3	+/- 2 kV	FC	1	С
X	+/- 3 - 4 kV	FC	1	C

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9 Rapid transient immunity tests in bursts on lines and terminals

Standard: EN 61000-4-4

Test equipment: Haefely PEFT Junior Decoupling network: Haefely 093 506-1

9.1 Test conditions

See wiring diagram

Rising time: 5ns Decreasing time: 50ns Burst duration : 15ms

Period: 300ms

Test duration: 60s minimum

9.2 Test results

9.2.1 On I/O signal, data and control ports

Level	$\mathbf{Voltage}$	remark	Behavor	Verdict
1	+/- 0.5 kV	FC	1	C
2	+/- 1 kV	FC	1	C
3	+/- 2 kV	FC	1	C
X	+/- 3 - 4 kV	FC	1	C

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10 Surge test immunity on circuits

Standard : EN 61000-4-5

Test equipment:

Profline système SCHAFFNER

NSG 2050, PNW 2055 Surge wave : $8/20\mu s$

10.1 Common mode test conditions

See wiring diagramm

Number of surges: 5 / phase angle Delay beetween surges: 1 /mn Source impedance: 12 Ohms Coupling: L-PE; N-PE; L-N-PE

10.2 Test results

Class	Voltage	Remark	Result	Verdict
1	$+/-0.5 \; kV$	FC	1	C
2	+/- 1 kV	FC	1	C
3	+/- 2 kV	FC	1	С
X	+/- 3 - 4 kV	FC	1	C

10.3 Differentiel mode test conditions

Nomber of surges : 5

Delay beetween surges: 1 /mn Source impedance : 2 Ohms

10.4 Test results

Class	$\mathbf{Voltage}$	Remark	Result	Verdict
1	+/- 0.5 kV	FC	1	С
2	+/- 1 kV	FC	1	С

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11 Surge test immunity on on lines and terminals

Standard : EN 61000-4-5

Test equipment: Profline système SCHAFFNER

NSG 2050 / PNW 2055 Surge wave: $8/20\mu$ s

Coupling network CDN 117, INA 170, INA 2055

11.1 Test conditions

See wiring diagram

Number of surges: 5

Delay between surges: 1 min Source impedance: 2 ohms

Common mode: 40 Ohms + 0.5μ F

11.2 Surge test on lines and terminals

Class	Voltage	Remark	Result	Verdict
1	+/- 0.5 kV	FC	1	C
2	+/- 1 kV	FC	1	С
3	+/- 2 kV	FC	1	C
X	+/- 3 kV - 4kV	FC	1	С

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12 Electrostatic discharge immunity tests

12.1 Indirect contact discharges

Standard : EN 61000-4-2

Test equipment : Haefely PSB 25B Cd+Cs = 150pF ; Rd=330 Ohms

12.1.1 Test conditions

See wiring diagram

10 contact discharges per point on the horizontal plane

10 contact discharges per point on vertical plane

For test points location, refer §20

12.1.2 Test results

Discharges on horizontal plane

Points	Voltage	Remark	Result	Verdict
1–4	+/- 4 kV	FC	1	C
1-4	+/- 5 kV	FC	1	C
1–4	+/- 6 kV	FC	1	C
1–4	+/- 8 kV	FC	1	C

Discharges on vertical plane

Points	Voltage	remark	Result	Verdict
1–4	+/- 4 kV	FC	1	С
1–4	+/- 5 kV	FC	1	С
1–4	+/- 6 kV	FC	1	С
1–4	+/- 8 kV	FC	1	С



12.2 Direct discharges

12.2.1 Test conditions

See wiring diagram 10 contact discharges per point 10 discharges per point in the air

For test points location, refer $\S 20$

12.2.2 Test results

Air discharges

Points	Voltage	Remark	Results	verdict
1 à 5	+/- 4 kV	FC	1	С
1 à 5	+/- 8 kV	FC	1	С
1 à 5	+/- 12 kV	FC	1	С
1 à 5	+/- 15 kV	FC	1	C

Contact discharges

Points	Voltage	Remark	Result	Verdict
1 à 5	+/- 4 kV	FC	1	С
1 à 5	+/- 5 kV	FC	1	С
1 à 5	+/- 6 kV	FC	1	С
1 à 5	+/- 8 kV	FC	1	C

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13 Radiated, radio-frequency, electromagnetic field immunity test

Standard : EN 61000-4-3

Test equipment :

SML02 ROHDE & SCHWARZ AmplifierWA1000

Antenne AS2 ; probe PCB Probe H-fied: PR 1000

13.1 Test conditions

See wiring diagram

Severity : 3V/m ou 10V/m Frequency range: 30MHz à 1Ghz Modulation: 80% 1kHz sinusoîdal

13.2 Test results

Level	Remark	Result	Verdict
3 V/m	FC	1	С
10V/m	FC	1	C

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14 Immunity to conducted disturbances, induced by radio-frequency fields

Standard : EN 61000-4-6

Test equipment:

SML02 ROHDE & SCHWARZ Amplificateur MRF 80

Coupling network: CDN 1 et attenuator - 6 dB

14.1 Test conditions

See wiring diagram

Level : 140 dB μ V / 10V rms ; 129.5 dB μ V / 3V rms Frequency range : balayage de 0.15 MHz à 80 MHz

Modulation: 80 % 1kHz sinusoîdal

Pulse modulation: 1Hz 0.5s ON; 0.5s OFF

14.2 test results

Level	Remark	Result	Verdict
$140 \mathrm{dB} \mu \mathrm{V}$	FC	1	C

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15 Voltage variations immunity tests

Standard : EN 61000-4-11

Test equipment: 108-TMX SCHAFFNER

Drived by: NSG 1006

15.1 Test conditions

See wiring diagram

Level: 230V + 10%, 230 V - 15%

15.2 Test results

Level	Duration	Remark	Result	Verdict
+10%	10 s	FC	1	\mathbf{C}
-15%	10 s	FC	1	С

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16 Voltage dips, short interruptions immunity tests

Standard : EN 61000-4-11

Test equipment: 108-TMX SCHAFFNER

Drived by: NSG 1006

16.1 Test conditions

See wiring diagram

Applied on main supply voltage circuit

Duration of voltage shorts: 10; 20; 100; 200 ms

Duration of volatge dips: 10; 20; 100 ms Number of voltage fluctuations: 3 /durée

Delay between fluctuations: 10s

16.2 Test results

Level	Duration	Remark	Result	Verdict
60%	0,5; 1;5;10 periods	FC	1	C
100%	0,5; 1; 5 periods	FC	1	С

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17 Radiated emission measurements

Standard : EN 55022 Classe B

17.1 Test conditions

See wiring diagram Bandwith : 120kHz

Frequency range: 30MHz - 1GHz

17.2 Test results

Level	Polarity	Remark	Verdict
Voir graphe	Horizontale	1	С
Voir graphe	Verticale	1	С

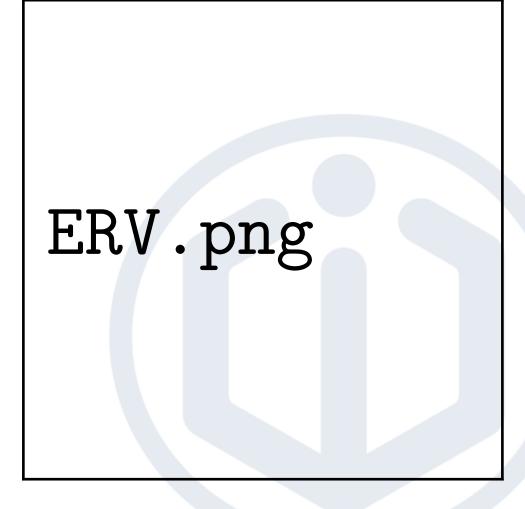
Measurements in horizontal polarity

ERH.png

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Measurements in vertical polarity



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18 Conducted emission measurements

Standard : 55022 Classe B

18.1 Test conditions

See wiring diagram Bandwith: 9 kHz

Frequency range: 0.15 MHz - 30 MHz

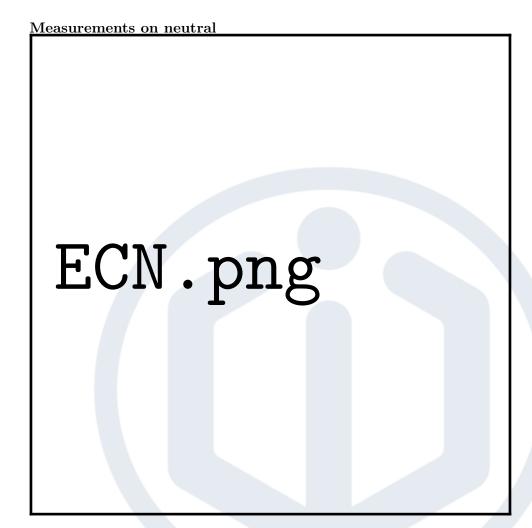
18.2 Test results

Level	Polarity	Remark	Verdict
See graph	Phase	1	С
See graph	Neutral	1	С

ECL.png

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19 Summary of test results and compliance notice

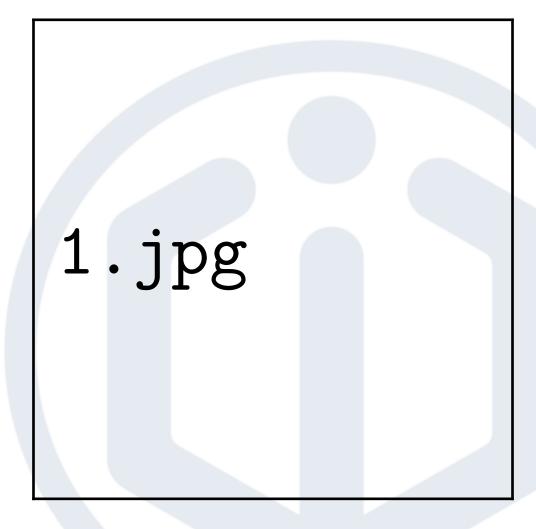
Test	Procedure	Result		
Immunity tests				
1. Repetitive electrical fast transients	EN 61000-4-4	С		
2. Surge immunity test	EN 61000-4-5	С		
3. Electrostatic discharge	EN 61000-4-2	С		
4. Radiated electromagnetic field	EN 61000-4-3	C		
5. Conducted disturbances	EN 61000-4-6	С		
6. Voltage dips and variations	EN 61000-4-11	C		
Emission measurements				
7. Radiated emissions	EN 55022	C		
8. Conducted disturbances	EN 55022	С		
Other emission measurements				
9. Harmonic current emissions	EN 61000-3-2	N/A		
10. Voltage fluctuations and flicker	EN 61000-3-3	N/A		

Le complies with european directive $2014/30/\mathrm{UE}$.

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20 Internal and external photographs of the EUT



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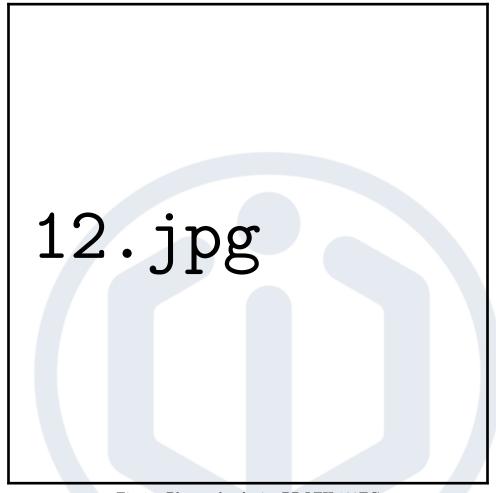


Fig 1 – Photos du clavier PROFIL100EC

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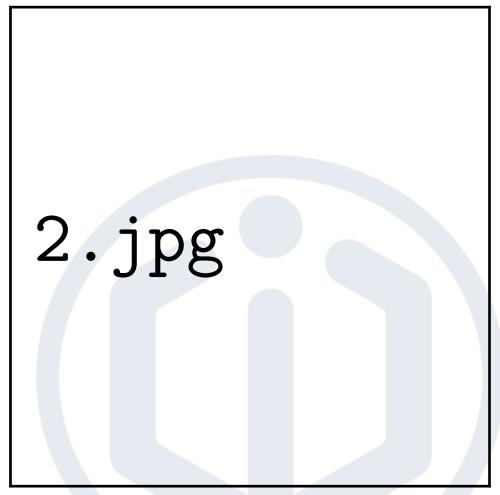


Fig 2 – Boitier électronique déporté

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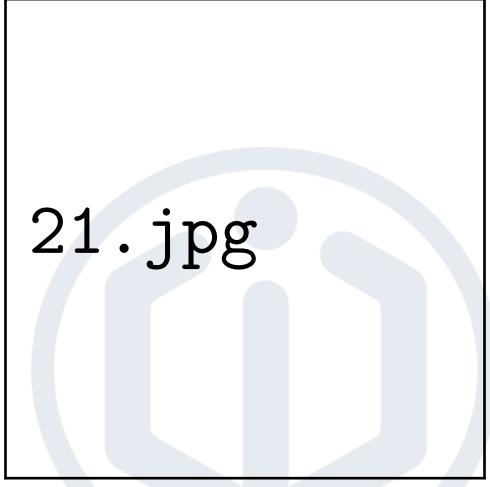
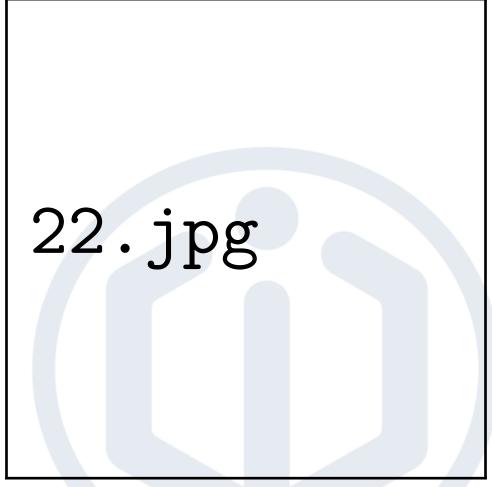


Fig3 – Carte électronique dans le boitier déporté

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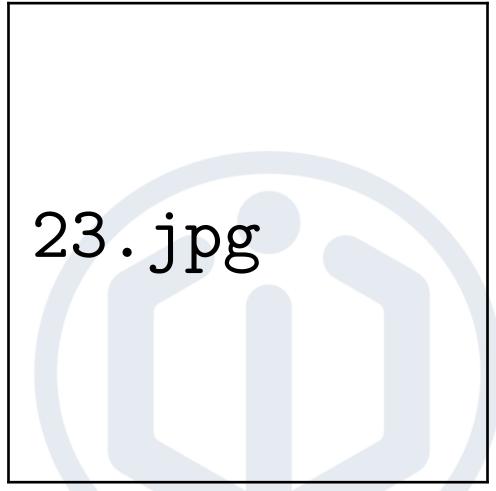




 ${\bf Fig}~4-{\bf Carte}~\acute{\bf e} {\bf lectronique}~{\bf face}~{\bf composants}$

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 ${\bf Fig}~{\bf 5-Carte~\acute{e}lectronique~face~soudures}$

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21 Test photographs



Fig 6 – Repetitive electrical fast transients test immunity on primary circuits

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Fig 7 – Conducted emissions measurement

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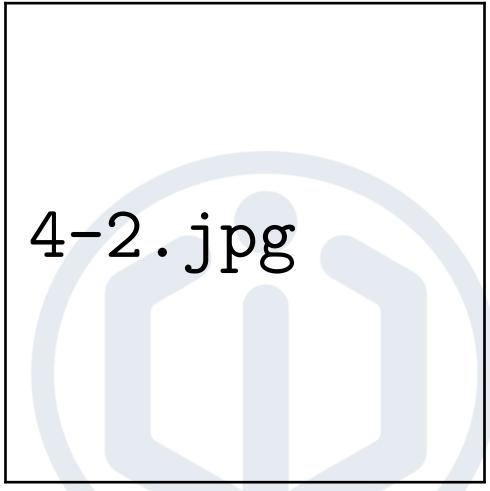


Fig 8 – Electrostatic discharge test immunity

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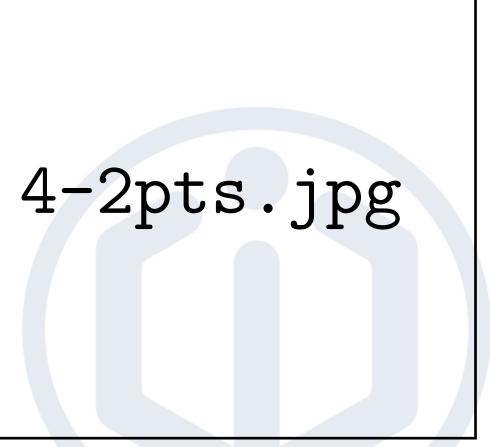


Fig 9 – Test points location for Electrostatic discharge test immunity

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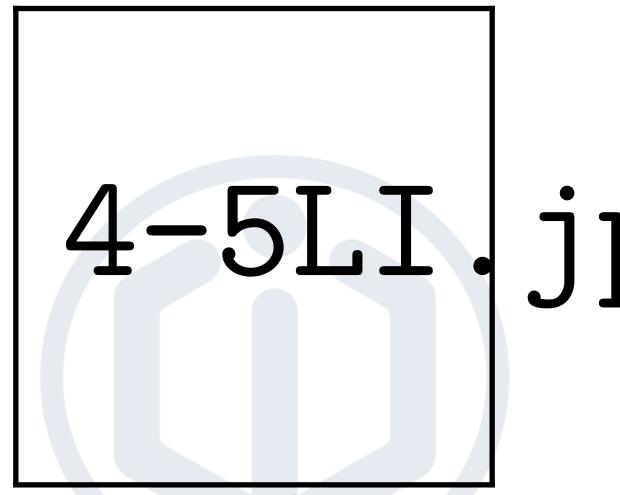
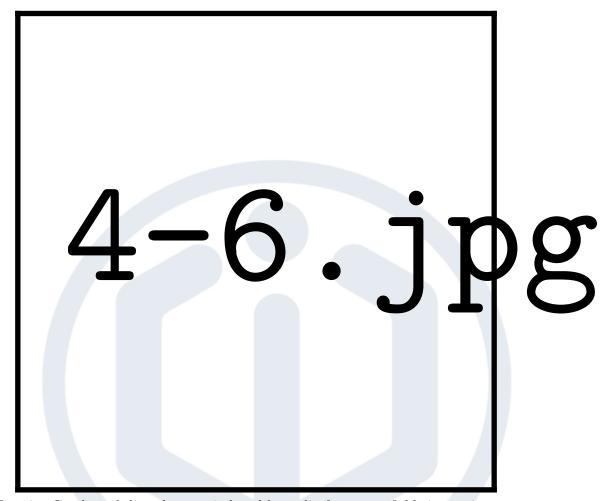


Fig 11 – Surge immunity test on I/O ports and terminals

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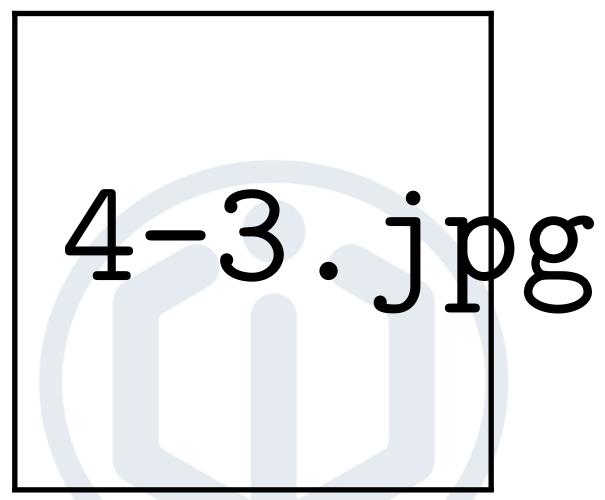




 ${\rm Fig}~12-{\rm Conducted~disturbances,~induced~by~radio-frequency~fields~immunity~test}$

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 ${\bf Fig~13-Radiated,~radiof requency,~electromagnetic~field~immunity~test}$

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